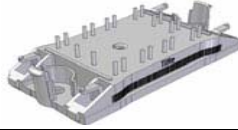
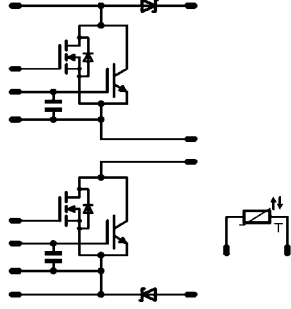


<i>flowBoost0</i>	600V/84A PS*
<div style="border: 1px solid black; padding: 5px; margin-bottom: 5px;"> <p style="text-align: center; background-color: #003366; color: white; margin: 0;">Features</p> <ul style="list-style-type: none"> *PS: 2x84A parallel switch (75A IGBT and 99mΩ C6) ultrafast IGBT with C6 MOSFET and SiC buck diodes symmetric booster ultra fast switching frequency low inductance layout </div> <div style="border: 1px solid black; padding: 5px; margin-bottom: 5px;"> <p style="text-align: center; background-color: #003366; color: white; margin: 0;">Target Applications</p> <ul style="list-style-type: none"> solar inverter UPS </div> <div style="border: 1px solid black; padding: 5px;"> <p style="text-align: center; background-color: #003366; color: white; margin: 0;">Types</p> <ul style="list-style-type: none"> FZ06NBA084FP </div>	<div style="border: 1px solid black; padding: 5px; margin-bottom: 5px;"> <p style="text-align: center; background-color: #003366; color: white; margin: 0;">flow0 12mm housing</p>  </div> <div style="border: 1px solid black; padding: 5px;"> <p style="text-align: center; background-color: #003366; color: white; margin: 0;">Schematic</p>  </div>

Maximum Ratings

T_j=25°C, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
Input Boost IGBT				
Collector-emitter break down voltage	V _{CE}		600	V
DC collector current	I _C	T _j =T _{jmax} T _h =80°C T _c =80°C	58 76	A
Repetitive peak collector current	I _{Cpulse}	t _p limited by T _{jmax}	225	A
Power dissipation per IGBT	P _{tot}	T _j =T _{jmax} T _h =80°C T _c =80°C	111 169	W
Gate-emitter peak voltage	V _{GE}		±20	V
Short circuit ratings	t _{SC} V _{CC}	T _j ≤125°C V _{GE} =15V	10 480	μs V
Maximum Junction Temperature	T _{jmax}		175	°C
Input Boost FWD				
Peak Repetitive Reverse Voltage	V _{RRM}	T _j =25°C	600	V
DC forward current	I _F	T _j =T _{jmax} T _h =80°C T _c =80°C	49 63	A
Repetitive peak forward current	I _{FRM}	t _p limited by T _{jmax}	210	A
Power dissipation per Diode	P _{tot}	T _j =T _{jmax} T _h =80°C T _c =80°C	88 133	W
Maximum Junction Temperature	T _{jmax}		175	°C

Maximum Ratings

 $T_j=25^{\circ}\text{C}$, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
-----------	--------	-----------	-------	------

Input Boost MOSFET

Drain to source breakdown voltage	V_{DS}		600	V
DC drain current	I_D	$T_j=T_{jmax}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	17 19	A
Pulsed drain current	I_{Dpulse}	t_p limited by T_{jmax} $T_c=25^{\circ}\text{C}$	112	A
Power dissipation	P_{tot}	$T_j=T_{jmax}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	111 169	W
Gate-source peak voltage	V_{gs}		± 20	V
Maximum Junction Temperature	T_{jmax}		150	$^{\circ}\text{C}$

Thermal Properties

Storage temperature	T_{stg}		-40...+125	$^{\circ}\text{C}$
Operation temperature under switching condition	T_{op}		-40...+($T_{jmax} - 25$)	$^{\circ}\text{C}$

Insulation Properties

Insulation voltage	V_{is}	$t=2s$ DC voltage	4000	V
Creepage distance			min 12,7	mm
Clearance			min 12,7	mm

Characteristic Values

Parameter	Symbol	Conditions				Value			Unit	
		V_{GE} [V] or V_{GS} [V]	V_c [V] or V_{CE} [V] or V_{DS} [V]	I_c [A] or I_F [A] or I_b [A]	T_j	Min	Typ	Max		
Input Boost IGBT *										
Gate emitter threshold voltage	$V_{GE(th)}$	VCE=VGE			0,00025	$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$	3,5	4,5	6	V
Collector-emitter saturation voltage	$V_{CE(sat)}$		15		75	$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$		2,12 2,24	2,72	V
Collector-emitter cut-off current incl. Diode	I_{CES}		0	600		$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$			250	μA
Gate-emitter leakage current	I_{GES}		± 20	0		$T_j=25^\circ\text{C}$ $T_j=150^\circ\text{C}$			400	nA
Integrated Gate resistor	R_{gint}							none		Ω
Input capacitance	C_{ies}							4000		pF
Output capacitance	C_{oss}	f=1MHz	0	30		$T_j=25^\circ\text{C}$		400		pF
Reverse transfer capacitance	C_{rss}							115		pF
Gate charge	Q_{Gate}		15	400	75	$T_j=25^\circ\text{C}$		94		nC
Thermal resistance chip to heatsink per chip	R_{thJH}	Thermal grease thickness $\leq 50\mu\text{m}$ $\lambda = 1 \text{ W/mK}$						0,85		K/W

* see dynamic characteristic at MosFET

Input Boost FWD

Diode forward voltage	V_F				48	$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		1,55 1,69	1,75	V
Peak reverse recovery current	I_{RRM}					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		52 43		A
Reverse recovery time	t_{rr}					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		11 12		ns
Reverse recovered charge	Q_{rr}	Rgon=4 Ω **	15	350	77	$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		0,47 0,60		μC
Peak rate of fall of recovery current	$di(rec)_{max}/dt$					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		12292 9335		A/ μs
Reverse recovered energy	E_{rec}					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		0,078 0,128		mWs
Thermal resistance chip to heatsink per chip	R_{thJH}	Thermal grease thickness $\leq 50\mu\text{m}$ $\lambda = 1 \text{ W/mK}$						1,10		K/W

Input Boost MOSFET

Static drain to source ON resistance	$R_{ds(on)}$		10		15	$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		97 193		m Ω
Gate threshold voltage	$V_{(GS)th}$		$V_{DS}=V_{GS}$		0,00121	$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$	2,5	3	3,5	V
Gate to Source Leakage Current	I_{gss}		20	0		$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$			100	nA
Zero Gate Voltage Drain Current	I_{dss}		0	600		$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$			5	μA
Turn On Delay Time	$t_{d(ON)}$					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		17 16		ns
Rise Time	t_r					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		6 7		
Turn off delay time	$t_{d(OFF)}$					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		105 124		
Fall time	t_f	Rgon=4 Ω ** Rgoff=4 Ω **	15	350	77	$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		6 7		mWs
Turn-on energy loss per pulse	E_{on}					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		0,15 0,29		
Turn-off energy loss per pulse	E_{off}					$T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$		0,40 0,84		
Total gate charge	Q_g							119		nC
Gate to source charge	Q_{gs}		0-10	480	18,1	$T_j=25^\circ\text{C}$		14		
Gate to drain charge	Q_{gd}							61		
Input capacitance	C_{iss}	f=1MHz	0	100		$T_j=25^\circ\text{C}$		2660		pF
Output capacitance	C_{oss}							154		
Thermal resistance chip to heatsink per chip	R_{thJH}	Thermal grease thickness $\leq 50\mu\text{m}$ $\lambda = 1 \text{ W/mK}$						1,05		K/W

** see gate drive conditions at characteristic figures

Characteristic Values

Parameter	Symbol	Conditions					Value			Unit
		V_{GE} [V] or V_{GS} [V]	V_r [V] or V_{CE} [V] or V_{DS} [V]	I_c [A] or I_F [A] or I_b [A]	T_j	Min	Typ	Max		
IGBT gate capacitor										
C value	C							4,7		nF
Thermistor										
Rated resistance*	R_{25}	Tol. $\pm 13\%$				$T_j=25^\circ\text{C}$	19,1	22	24,9	k Ω
	R_{100}	Tol. $\pm 5\%$				$T_j=100^\circ\text{C}$	1411	1486	1560	Ω
Power dissipation	P					$T_j=25^\circ\text{C}$		210		mW
B-value	$B_{(25/100)}$	Tol. $\pm 3\%$				$T_j=25^\circ\text{C}$		4000		K

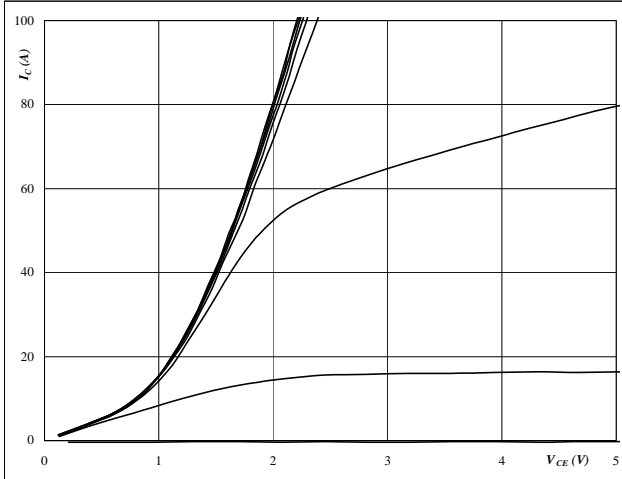
* see details on **Thermistor** charts on *Figure 2*.

Input Boost

Figure 1 IGBT+MOSFET

Typical output characteristics

$I_C = f(V_{CE})$

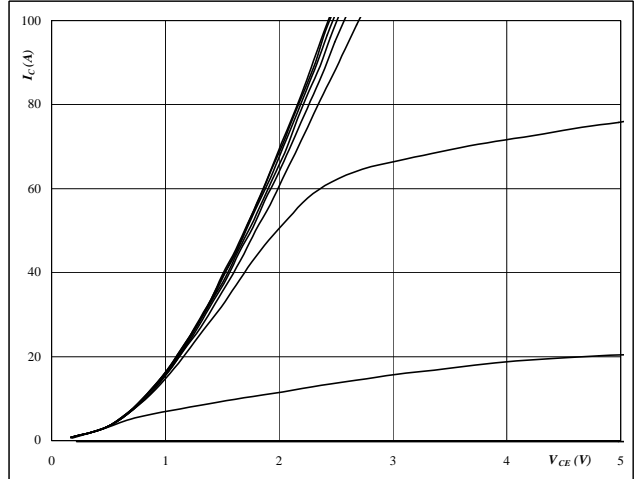


At
 $t_p = 250 \mu s$
 $T_j = 25 \text{ } ^\circ C$
 V_{GE} from 3 V to 19 V in steps of 2 V

Figure 2 IGBT+MOSFET

Typical output characteristics

$I_C = f(V_{CE})$

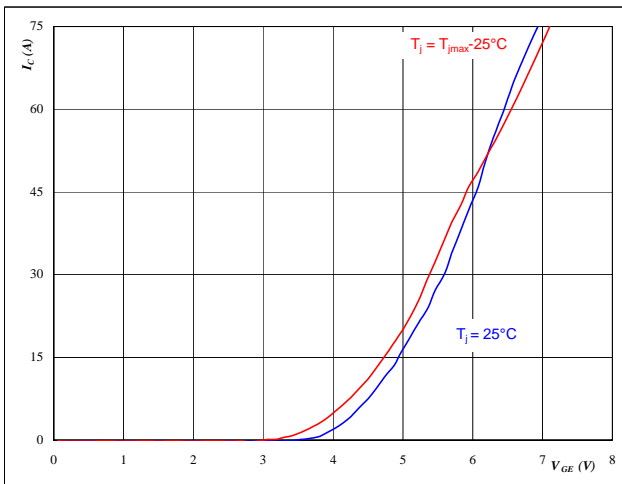


At
 $t_p = 250 \mu s$
 $T_j = 126 \text{ } ^\circ C$
 V_{GE} from 3 V to 19 V in steps of 2 V

Figure 3 IGBT+MOSFET

Typical transfer characteristics

$I_C = f(V_{GE})$

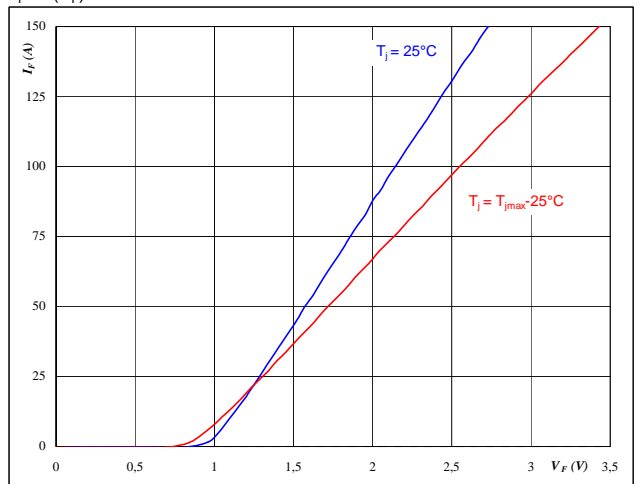


At
 $t_p = 250 \mu s$
 $V_{CE} = 10 \text{ V}$

Figure 4 FWD

Typical diode forward current as a function of forward voltage

$I_F = f(V_F)$

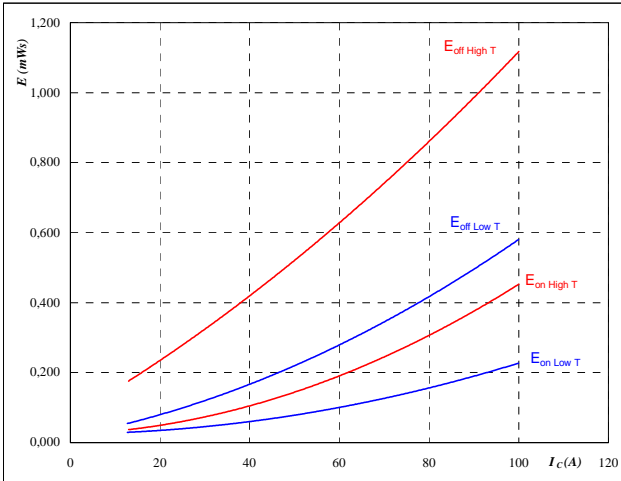


At
 $t_p = 250 \mu s$

Input Boost

Figure 5 IGBT+MOSFET

Typical switching energy losses
 as a function of collector current
 $E = f(I_C)$



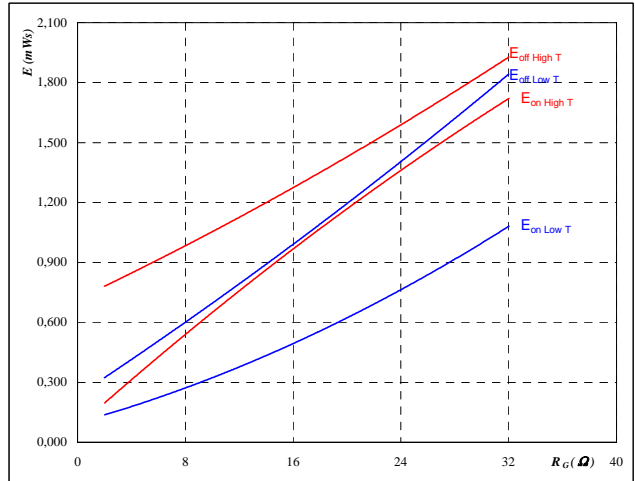
With an inductive load at

$T_j = 25/126 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$
 $R_{goff} = 4 \text{ } \Omega$

MOSFET turn off delayed by 100ns

Figure 6 IGBT+MOSFET

Typical switching energy losses
 as a function of gate resistor
 $E = f(R_G)$



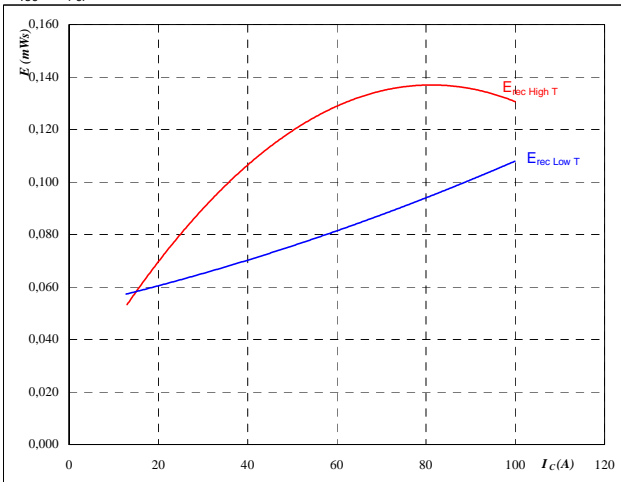
With an inductive load at

$T_j = 25/126 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = 15 \text{ V}$
 $I_C = 78 \text{ A}$

MOSFET turn off delayed by 100ns

Figure 7 FWD

Typical reverse recovery energy loss
 as a function of collector current
 $E_{rec} = f(I_C)$



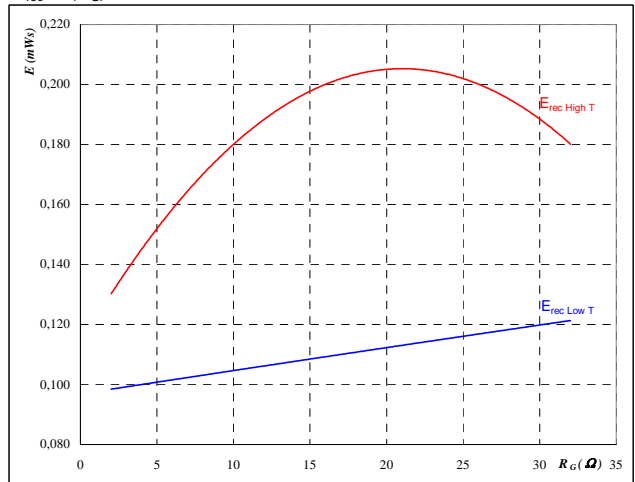
With an inductive load at

$T_j = 25/126 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$

MOSFET turn off delayed by 100ns

Figure 8 FWD

Typical reverse recovery energy loss
 as a function of gate resistor
 $E_{rec} = f(R_G)$



With an inductive load at

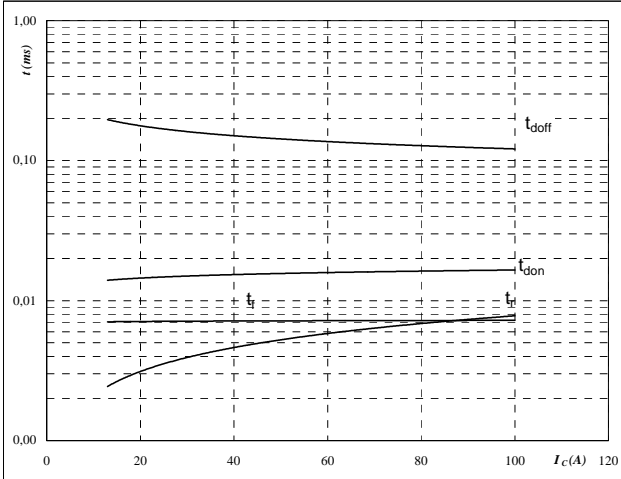
$T_j = 25/126 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = 15 \text{ V}$
 $I_C = 78 \text{ A}$

MOSFET turn off delayed by 100ns

Input Boost

Figure 9 IGBT+MOSFET

Typical switching times as a function of collector current
 $t = f(I_C)$



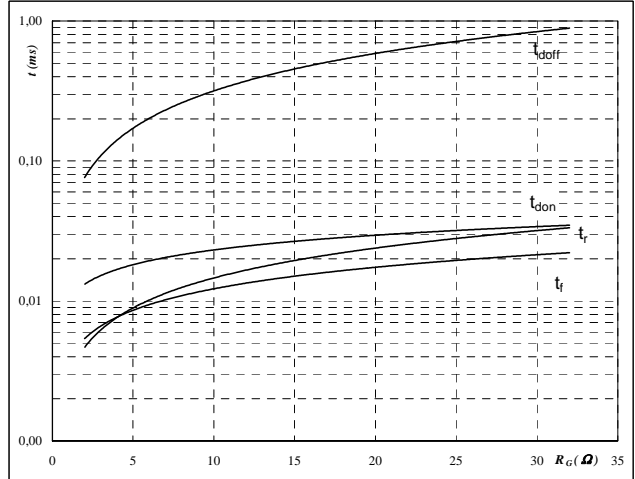
With an inductive load at

$T_j = 126 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$
 $R_{goff} = 4 \text{ } \Omega$

MOSFET turn off delayed by 100ns

Figure 10 IGBT+MOSFET

Typical switching times as a function of gate resistor
 $t = f(R_G)$



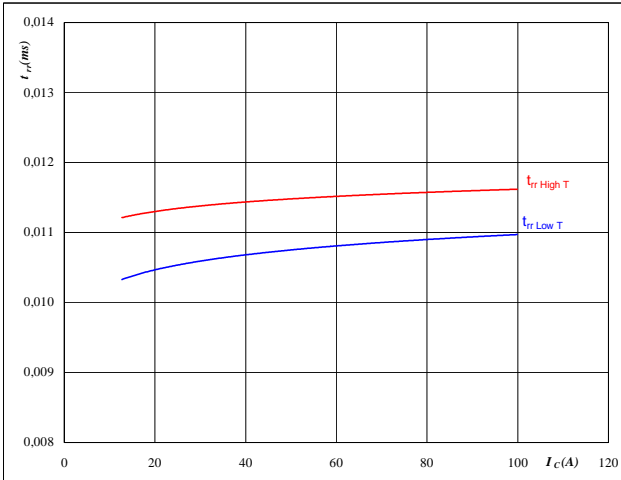
With an inductive load at

$T_j = 126 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = 15 \text{ V}$
 $I_C = 78 \text{ A}$

MOSFET turn off delayed by 100ns

Figure 11 FWD

Typical reverse recovery time as a function of collector current
 $t_{rr} = f(I_C)$

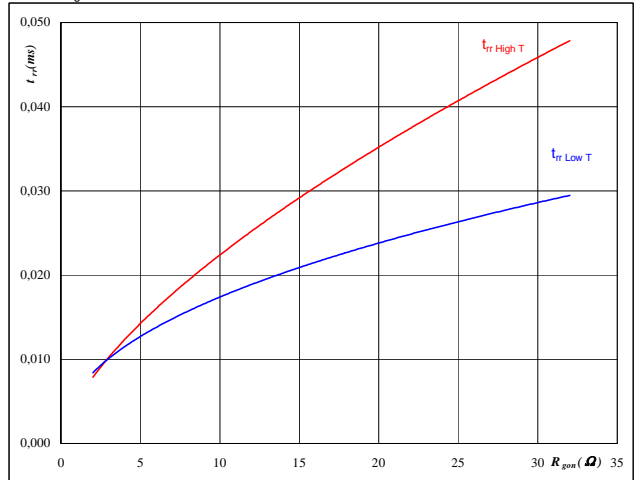


At

$T_j = 25/126 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$

Figure 12 FWD

Typical reverse recovery time as a function of IGBT turn on gate resistor
 $t_{rr} = f(R_{gon})$



At

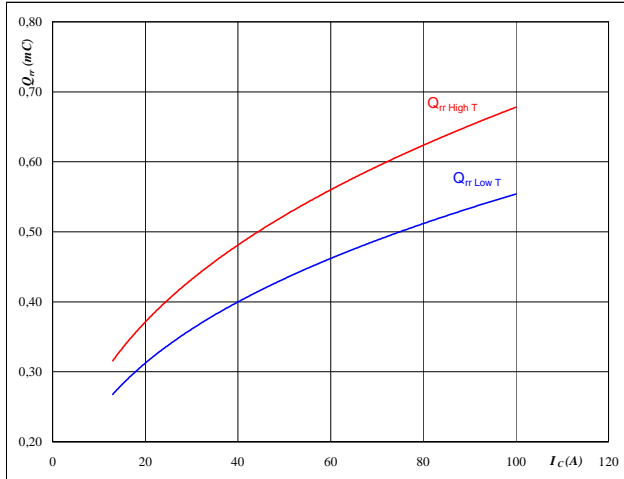
$T_j = 25/126 \text{ } ^\circ\text{C}$
 $V_R = 350 \text{ V}$
 $I_F = 78 \text{ A}$
 $V_{GE} = 15 \text{ V}$

Input Boost

Figure 13 FWD

Typical reverse recovery charge as a function of collector current

$$Q_{rr} = f(I_C)$$



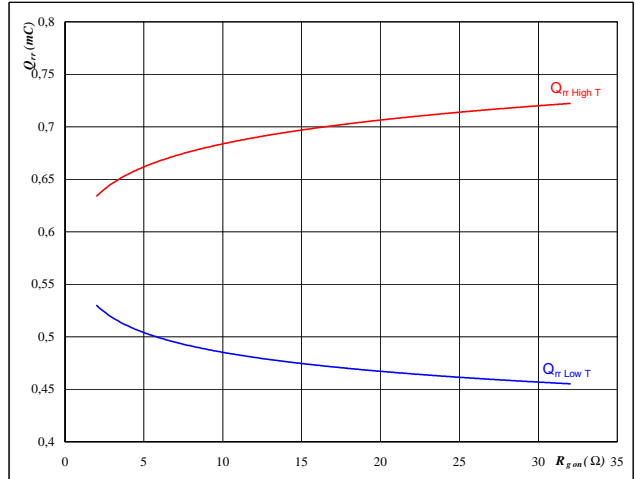
At

$T_j =$	25/126	°C
$V_{CE} =$	350	V
$V_{GE} =$	15	V
$R_{gon} =$	4	Ω

Figure 14 FWD

Typical reverse recovery charge as a function of IGBT turn on gate resistor

$$Q_{rr} = f(R_{gon})$$



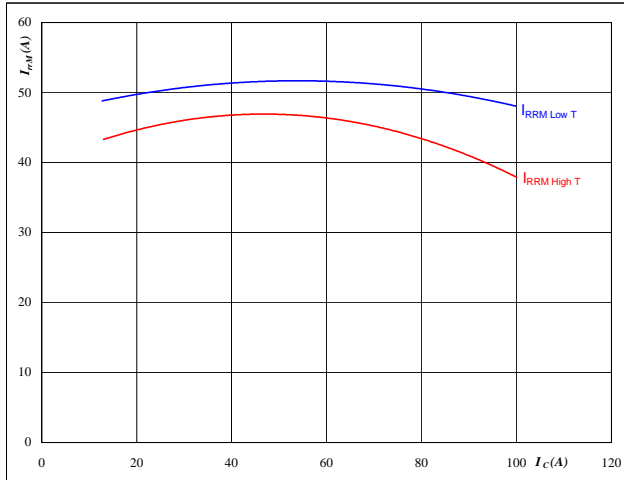
At

$T_j =$	25/126	°C
$V_R =$	350	V
$I_F =$	78	A
$V_{GE} =$	15	V

Figure 15 FWD

Typical reverse recovery current as a function of collector current

$$I_{RRM} = f(I_C)$$



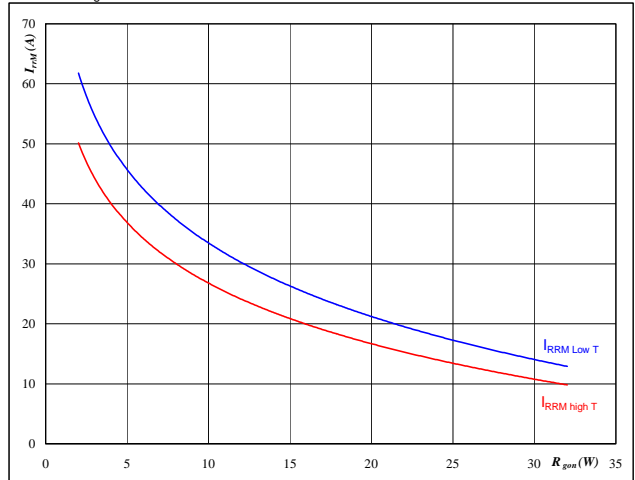
At

$T_j =$	25/126	°C
$V_{CE} =$	350	V
$V_{GE} =$	15	V
$R_{gon} =$	4	Ω

Figure 16 FWD

Typical reverse recovery current as a function of IGBT turn on gate resistor

$$I_{RRM} = f(R_{gon})$$



At

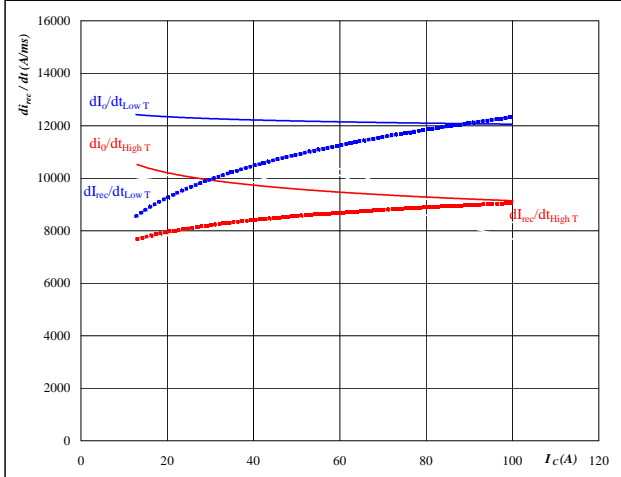
$T_j =$	25/126	°C
$V_R =$	350	V
$I_F =$	78	A
$V_{GE} =$	15	V

Input Boost

Figure 17 FWD

Typical rate of fall of forward and reverse recovery current as a function of collector current

$$di_o/dt, di_{rec}/dt = f(I_c)$$

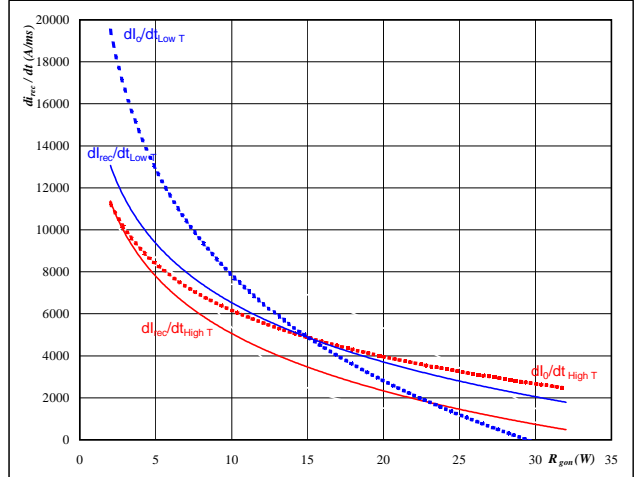


At
 $T_j = 25/126 \text{ } ^\circ\text{C}$
 $V_{CE} = 350 \text{ V}$
 $V_{GE} = 15 \text{ V}$
 $R_{gon} = 4 \text{ } \Omega$

Figure 18 FWD

Typical rate of fall of forward and reverse recovery current as a function of IGBT turn on gate resistor

$$di_o/dt, di_{rec}/dt = f(R_{gon})$$

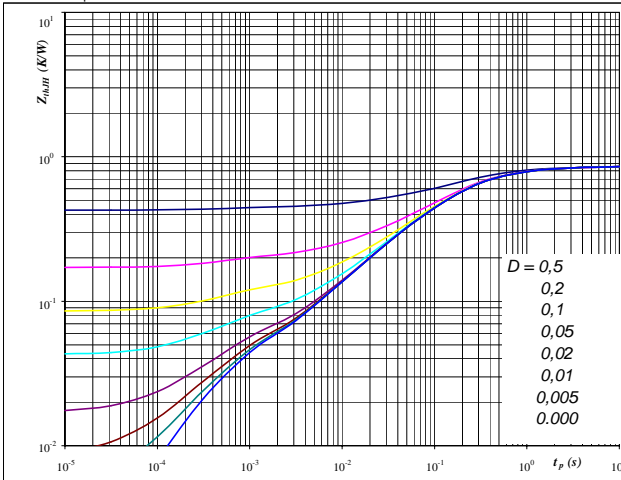


At
 $T_j = 25/126 \text{ } ^\circ\text{C}$
 $V_R = 350 \text{ V}$
 $I_F = 78 \text{ A}$
 $V_{GE} = 15 \text{ V}$

Figure 19 IGBT

IGBT transient thermal impedance as a function of pulse width

$$Z_{thJH} = f(t_p)$$



At
 $D = t_p / T$
 $R_{thJH} = 0,85 \text{ K/W}$

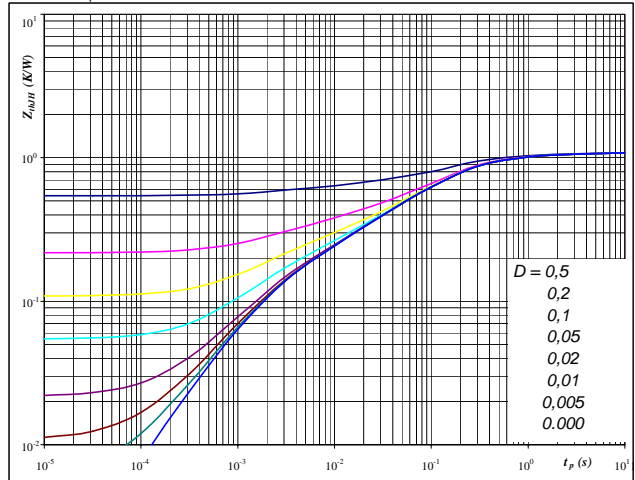
IGBT thermal model values

R (C/W)	Tau (s)
0,10	1,8E+00
0,32	2,8E-01
0,30	8,4E-02
0,09	1,2E-02
0,04	5,0E-04

Figure 20 FWD

FRED transient thermal impedance as a function of pulse width

$$Z_{thJH} = f(t_p)$$



At
 $D = t_p / T$
 $R_{thJH} = 1,09 \text{ K/W}$

FRED thermal model values

R (C/W)	Tau (s)
0,06	4,1E+00
0,22	5,0E-01
0,55	1,1E-01
0,16	1,1E-02
0,10	1,6E-03

Input Boost

Figure 21 IGBT

Power dissipation as a function of heatsink temperature

$$P_{tot} = f(T_h)$$

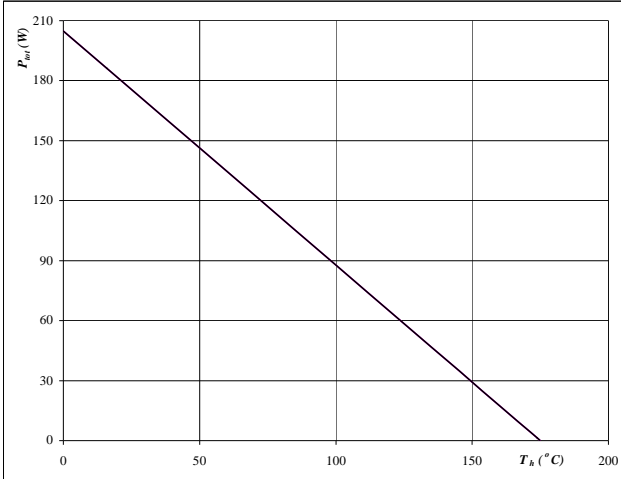

At
 $T_j = 175$ °C

Figure 22 IGBT

Collector current as a function of heatsink temperature

$$I_C = f(T_h)$$

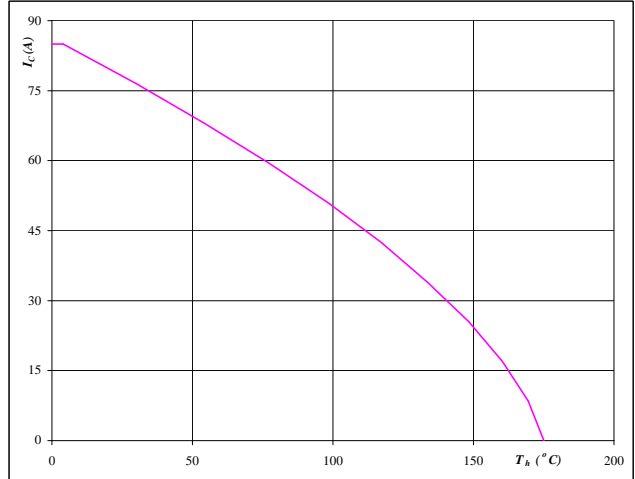

At
 $T_j = 175$ °C
 $V_{GE} = 15$ V

Figure 23 FWD

Power dissipation as a function of heatsink temperature

$$P_{tot} = f(T_h)$$

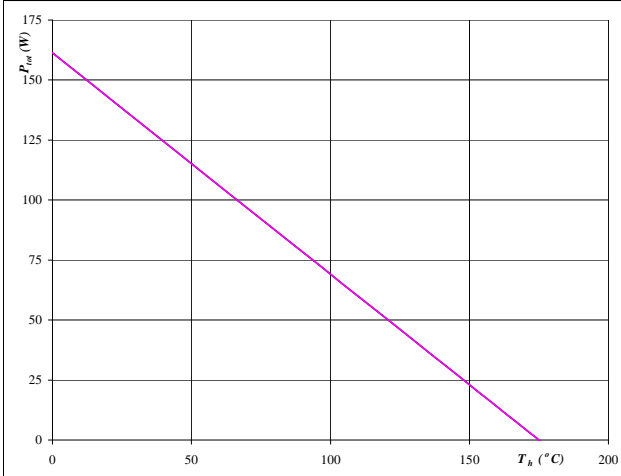
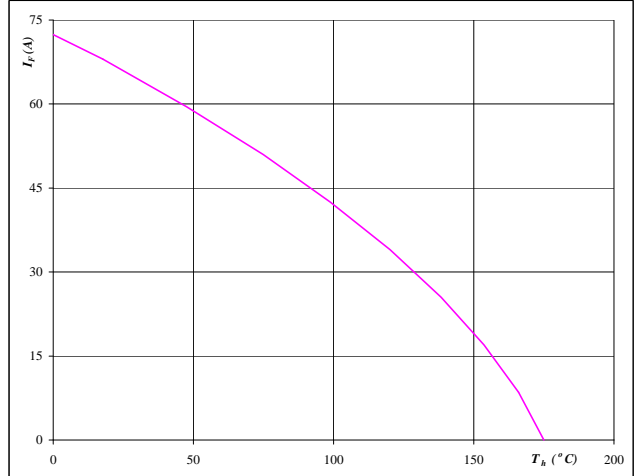

At
 $T_j = 175$ °C

Figure 24 FWD

Forward current as a function of heatsink temperature

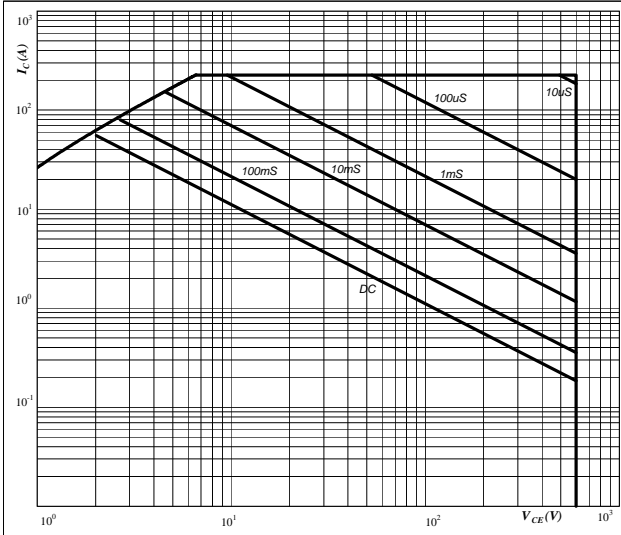
$$I_F = f(T_h)$$


At
 $T_j = 175$ °C

Input Boost

Figure 25 IGBT

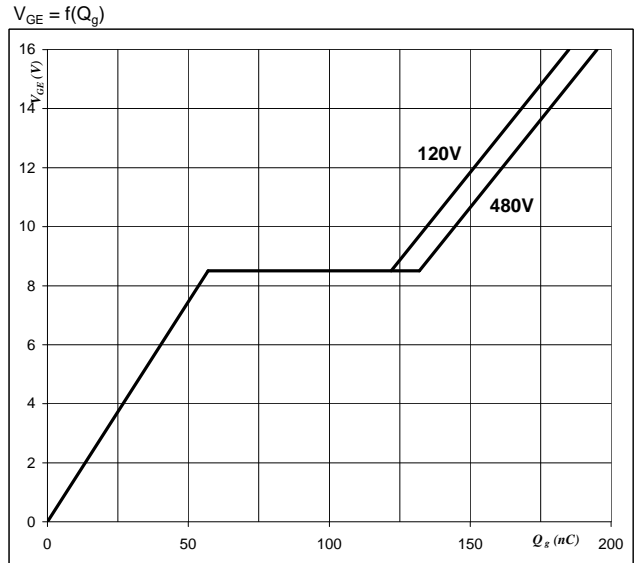
Safe operating area
of collector-emitter voltage
 $I_C = f(V_{CE})$



At
D = single pulse
Th = 80 °C
V_{GE} = 15 V
T_j = T_{jmax} °C

Figure 26 IGBT

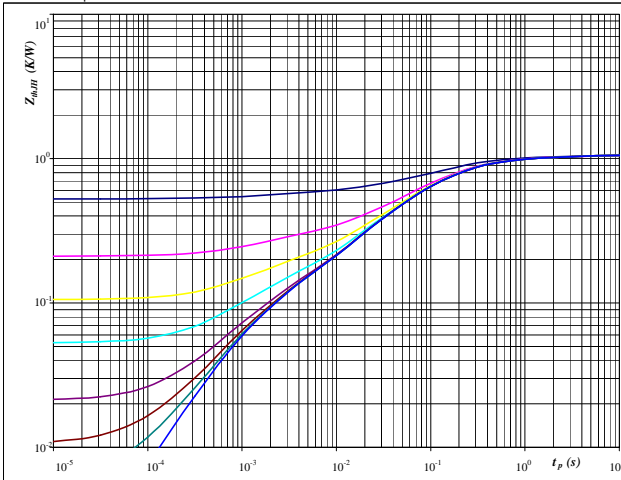
Gate voltage vs Gate charge



At
I_{G(REF)} = 1mA, R_L = 15Ω

Figure 27 MOSFET

MOSFET transient thermal impedance
as a function of pulse width
 $Z_{thJH} = f(t_p)$



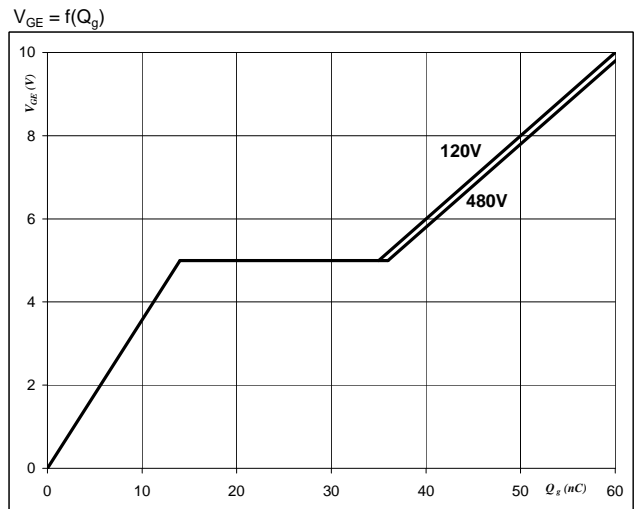
At
D = t_p / T
R_{thJH} = 1,05 K/W

MOSFET thermal model values

R (C/W)	Tau (s)
0,06	3,4E+00
0,23	4,0E-01
0,53	8,8E-02
0,15	1,5E-02
0,08	1,3E-03
0,05	4,7E-04

Figure 28 MOSFET

Gate voltage vs Gate charge

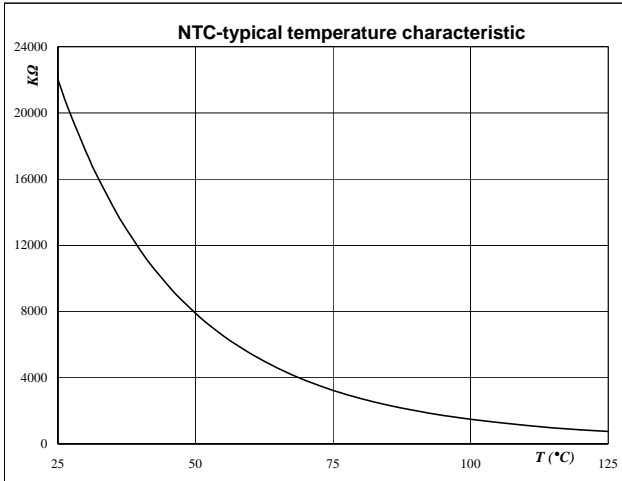


At
I_C = 18 A

Thermistor

Figure 1 Thermistor

Typical NTC characteristic
 as a function of temperature
 $R_T = f(T)$


Figure 2 Thermistor

Typical NTC resistance values

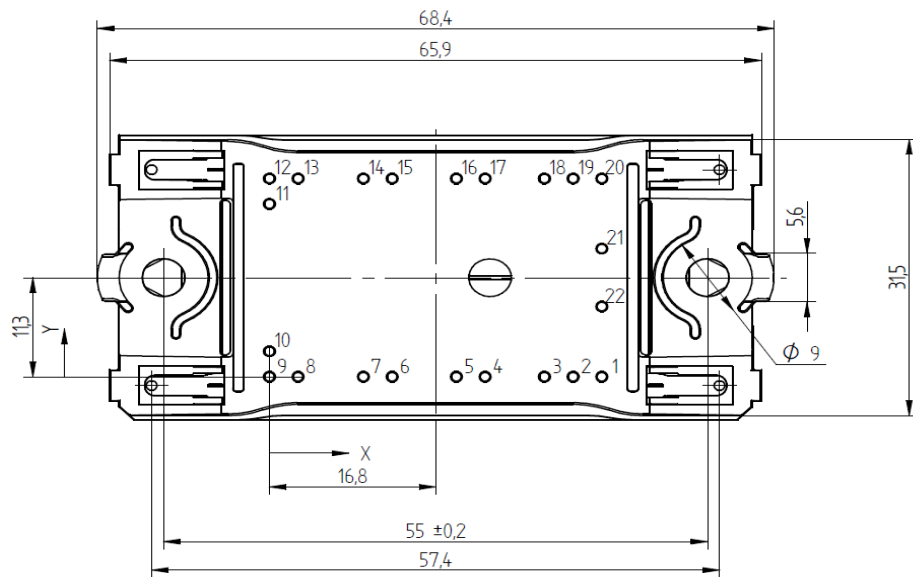
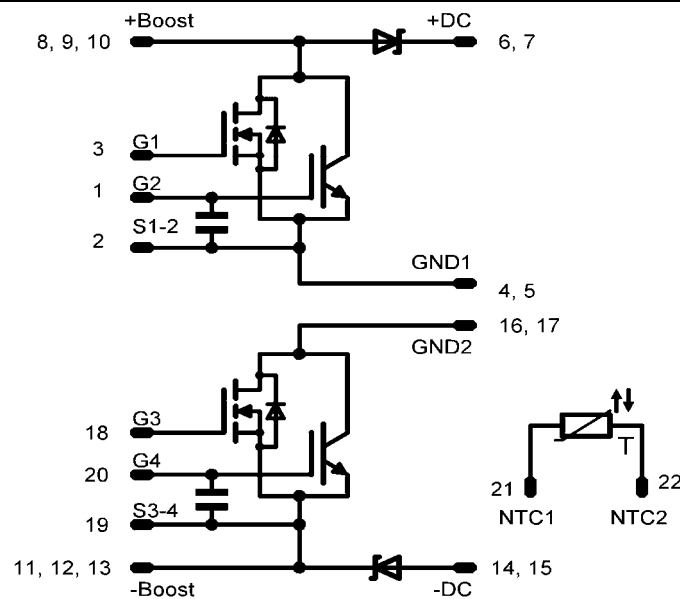
$$R(T) = R_{25} \cdot e^{\left(B_{25/100} \left(\frac{1}{T} - \frac{1}{T_{25}} \right) \right)} \quad [\Omega]$$

Ordering Code and Marking - Outline - Pinout
Ordering Code & Marking

Version	Ordering Code	in DataMatrix as	in packaging barcode as
without thermal paste 12mm housing	10-FZ06NBA084FP-M306L48	M306L48	M306L48

Outline

Pin table		
Pin	X	Y
1	33,6	0
2	30,7	0
3	27,8	0
4	21,8	0
5	18,9	0
6	12,4	0
7	9,5	0
8	2,9	0
9	0	0
10	0	2,9
11	0	19,7
12	0	22,6
13	2,9	22,6
14	9,5	22,6
15	12,4	22,6
16	18,9	22,6
17	21,8	22,6
18	27,8	22,6
19	30,7	22,6
20	33,6	22,6
21	33,6	14,6
22	33,6	8


Pinout


PRODUCT STATUS DEFINITIONS

Datasheet Status	Product Status	Definition
Target	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice. The data contained is exclusively intended for technically trained staff.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data may be published at a later date. Vincotech reserves the right to make changes at any time without notice in order to improve design. The data contained is exclusively intended for technically trained staff.
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